

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/724,918 | Applicant(s)/Patent Under Reexamination USUI ET AL. | |
| | Examiner Michael K. Luhrs | Art Unit 2824 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,602,803 | 08-2003 | Yew et al. | 438/780 |
| | B | US-6,689,641 | 02-2004 | Ohta et al. | 438/121 |
| | C | US-6,074,895 | 06-2000 | Dery et al. | 438/108 |
| | D | US-6,512,295 | 01-2003 | Gaynes et al. | 257/738 |
| | E | US-6,596,559 | 07-2003 | Kodnani et al. | 438/106 |
| | F | US-6,383,893 | 05-2002 | Begle et al. | 438/460 |
| | G | US-6,338,980 | 01-2002 | Satoh, Tetsuo | 438/106 |
| | H | US-2004/0006869 | 01-2004 | Igarashi et al. | 29/847 |
| | I | US-2002/0106831 | 08-2002 | Tago et al. | 438/106 |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.